

# IEEE Recommended Practice for Routine Impulse Tests for Distribution Transformers

IEEE Power and Energy Society

Sponsored by the  
Transformers Committee

---

IEEE  
3 Park Avenue  
New York, NY 10016-5997  
USA

**IEEE Std C57.138™-2016**  
(Revision of IEEE Std C57.138-1998)

# **IEEE Recommended Practice for Routine Impulse Tests for Distribution Transformers**

Sponsor

**Transformers Committee**  
of the  
**IEEE Power and Energy Society**

Approved 7 December 2016

**IEEE-SA Standards Board**

Currently in preview, click buy full version

**Abstract:** General test procedures for performing routine quality control tests that are suitable for high-volume, production line testing are included in this recommended practice. Transformer connections, test methods, circuit configurations, and failure detection methods are addressed. This recommended practice covers liquid-immersed, single- and three-phase distribution transformers.

**Keywords:** distribution transformers, IEEE C57.138™, production line testing, routine test

---

The Institute of Electrical and Electronics Engineers, Inc.  
3 Park Avenue, New York, NY 10016-5997, USA

Copyright © 2017 by The Institute of Electrical and Electronics Engineers, Inc.  
All rights reserved. Published 15 March 2017. Printed in the United States of America.

IEEE is a registered trademark in the U.S. Patent & Trademark Office, owned by The Institute of Electrical and Electronics Engineers, Incorporated.

PDF: ISBN 978-1-5044-3710-3 STD22405  
Print: ISBN 978-1-5044-3711-0 STDPD22405

*IEEE prohibits discrimination, harassment, and bullying.*

For more information, visit <http://www.ieee.org/web/aboutus/whatis/policies/p9-26.html>.

No part of this publication may be reproduced in any form, in an electronic retrieval system or otherwise, without the prior written permission of the publisher.

## Important Notices and Disclaimers Concerning IEEE Standards Documents

IEEE documents are made available for use subject to important notices and legal disclaimers. These notices and disclaimers, or a reference to this page, appear in all standards and may be found under the heading “Important Notices and Disclaimers Concerning IEEE Standards Documents.” They can also be obtained on request from IEEE or viewed at <http://standards.ieee.org/IPR/disclaimers.html>.

### Notice and Disclaimer of Liability Concerning the Use of IEEE Standards Documents

IEEE Standards documents (standards, recommended practices, and guides), both full-use and trial-use, are developed within IEEE Societies and the Standards Coordinating Committees of the IEEE Standards Association (“IEEE-SA”) Standards Board. IEEE (“the Institute”) develops its standards through a consensus development process, approved by the American National Standards Institute (“ANSI”), which brings together volunteers representing varied viewpoints and interests to achieve the final product. IEEE Standards documents developed through scientific, academic, and industry-based technical working groups. Volunteers in IEEE working groups are not necessarily members of the Institute and participate without compensation from IEEE. While IEEE administers the process and establishes rules to promote fairness in the consensus development process, IEEE does not independently evaluate, test, or verify the accuracy of any of the information or the soundness of any judgments contained in its standards.

IEEE Standards do not guarantee or ensure safety, security, health, or environmental protection, or ensure against interference with or from other devices or networks. Implementers and users of IEEE Standards documents are responsible for determining and complying with all appropriate safety, security, environmental, health, and interference protection practices and all applicable laws and regulations.

IEEE does not warrant or represent the accuracy or content of the material contained in its standards, and expressly disclaims all warranties (express, implied and statutory) not included in this or any other document relating to the standard, including, but not limited to, the warranties of: merchantability; fitness for a particular purpose; non-infringement; and quality, accuracy, effectiveness, currency, or completeness of material. In addition, IEEE disclaims any and all conditions relating to: results; and workmanlike effort. IEEE standards documents are supplied “AS IS” and “WITH ALL FAULTS.”

Use of an IEEE standard is wholly voluntary. The existence of an IEEE standard does not imply that there are no other ways to produce, test, measure, purchase, market, or provide other goods and services related to the scope of the IEEE standard. Furthermore, the viewpoint expressed at the time a standard is approved and issued is subject to change from time to time about through developments in the state of the art and comments received from users of the standard.

In publishing and making its standards available, IEEE is not suggesting or rendering professional or other services for, or on behalf of, any person or entity nor is IEEE undertaking to perform any duty owed by any other person or entity to another. Any person utilizing any IEEE Standards document, should rely upon his or her own independent judgment in the exercise of reasonable care in any given circumstances or, as appropriate, seek the advice of a competent professional in determining the appropriateness of a given IEEE standard.

IN NO EVENT SHALL IEEE BE LIABLE FOR ANY DIRECT, INDIRECT, INCIDENTAL, SPECIAL, EXEMPLARY, OR CONSEQUENTIAL DAMAGES (INCLUDING, BUT NOT LIMITED TO: PROCUREMENT OF SUBSTITUTE GOODS OR SERVICES; LOSS OF USE, DATA, OR PROFITS; OR BUSINESS INTERRUPTION) HOWEVER CAUSED AND ON ANY THEORY OF LIABILITY, WHETHER IN CONTRACT, STRICT LIABILITY, OR TORT (INCLUDING NEGLIGENCE OR OTHERWISE) ARISING IN ANY WAY OUT OF THE PUBLICATION, USE OF, OR RELIANCE UPON ANY STANDARD, EVEN IF ADVISED OF THE POSSIBILITY OF SUCH DAMAGE AND REGARDLESS OF WHETHER SUCH DAMAGE WAS FORESEEABLE.

## Translations

The IEEE consensus development process involves the review of documents in English only. In the event that an IEEE standard is translated, only the English version published by IEEE should be considered the approved IEEE standard.

## Official statements

A statement, written or oral, that is not processed in accordance with the IEEE-SA Standards Board Operations Manual shall not be considered or inferred to be the official position of IEEE or any of its committees and shall not be considered to be, or be relied upon as, a formal position of IEEE. At lectures, symposia, seminars, or educational courses, an individual presenting information on IEEE standards shall make it clear that his or her views should be considered the personal views of that individual rather than the formal position of IEEE.

## Comments on standards

Comments for revision of IEEE Standards documents are welcome from any interested party, regardless of membership affiliation with IEEE. However, IEEE does not provide consulting information or advice pertaining to IEEE Standards documents. Suggestions for changes in documents should be in the form of a proposed change of text, together with appropriate supporting comments. Since IEEE standards represent a consensus of concerned interests, it is important that any responses to comments and questions also receive the concurrence of a balance of interests. For this reason, IEEE and the members of its Societies and Standards Coordinating Committees are not able to provide an instant response to comments or questions except in those cases where the matter has previously been addressed. For the same reason, IEEE does not respond to interpretation requests. Any person who would like to participate in revisions to an IEEE standard is welcome to join the relevant IEEE working group.

Comments on standards should be submitted to the following address:

Secretary, IEEE-SA Standards Board  
445 Hoes Lane  
Piscataway, NJ 08854 USA

## Laws and regulations

Users of IEEE Standards documents should consult all applicable laws and regulations. Compliance with the provisions of any IEEE Standards document does not imply compliance to any applicable regulatory requirements. Implementers of the standard are responsible for observing or referring to the applicable regulatory requirements. IEEE does not, by the publication of its standards, intend to urge action that is not in compliance with applicable laws, and these documents may not be construed as doing so.

## Copyrights

IEEE draft and approved standards are copyrighted by IEEE under US and international copyright laws. They are made available by IEEE and are adopted for a wide variety of both public and private uses. These include both use, by reference, in laws and regulations, and use in private self-regulation, standardization, and the promotion of engineering practices and methods. By making these documents available for use and adoption by public authorities and private users, IEEE does not waive any rights in copyright to the documents.

## Photocopies

Subject to payment of the appropriate fee, IEEE will grant users a limited, non-exclusive license to photocopy portions of any individual standard for company or organizational internal use or individual, non-commercial use only. To arrange for payment of licensing fees, please contact Copyright Clearance Center, Customer Service, 222 Rosewood Drive, Danvers, MA 01923 USA; +1 978 750 8400. Permission to photocopy portions of any individual standard for educational classroom use can also be obtained through the Copyright Clearance Center.

## Updating of IEEE Standards documents

Users of IEEE Standards documents should be aware that these documents may be superseded at any time by the issuance of new editions or may be amended from time to time through the issuance of amendments, corrigenda, or errata. An official IEEE document at any point in time consists of the current edition of the document together with any amendments, corrigenda, or errata then in effect.

Every IEEE standard is subjected to review at least every 10 years. When a document is more than 10 years old and has not undergone a revision process, it is reasonable to conclude that its contents, although still of some value, do not wholly reflect the present state of the art. Users are cautioned to check to determine that they have the latest edition of any IEEE standard.

In order to determine whether a given document is the current edition and whether it has been amended through the issuance of amendments, corrigenda, or errata, visit the IEEE Explore at <http://ieeexplore.ieee.org/> or contact IEEE at the address listed previously. For more information about the IEEE-SA or IEEE's standards development process, visit the IEEE-SA Website at <http://standards.ieee.org>.

## Errata

Errata, if any, for all IEEE standards can be accessed on the IEEE-SA Website at the following URL: <http://standards.ieee.org/findstds/errata/index.html>. Users are encouraged to check this URL for errata periodically.

## Patents

Attention is called to the possibility that implementation of this standard may require use of subject matter covered by patent rights. By publication of this standard, no position is taken by the IEEE with respect to the existence or validity of any patent rights in connection therewith. If a patent holder or patent applicant has filed a statement of assurance via an Accepted Letter of Assurance, then the statement is listed on the IEEE-SA Website at <http://standards.ieee.org/about/sasb/patcom/patents.html>. Letters of Assurance may indicate whether the Submitter is willing or unwilling to grant licenses under patent rights without compensation or under reasonable terms, with reasonable terms and conditions that are demonstrably free of any unfair discrimination to applicants desiring to obtain such licenses.

Essential Patent Claims may exist for which a Letter of Assurance has not been received. The IEEE is not responsible for identifying Essential Patent Claims for which a license may be required, for conducting inquiries into the legal validity or scope of Patent Claims, or determining whether any licensing terms or conditions provided in connection with submission of a Letter of Assurance, if any, or in any licensing agreements are reasonable or non-discriminatory. Users of this standard are expressly advised that determination of the validity of any patent rights, and the risk of infringement of such rights, is entirely their own responsibility. Further information may be obtained from the IEEE Standards Association.

## Participants

At the time this IEEE recommended practice was completed, the PC57.138 Working Group had the following membership:

**Arthur Molden, *Chair***  
**Susmitha D. Tarlapally, *Vice Chair***

Alain Bolliger  
Jeffrey Britton  
John Crotty

Michael Franchek  
Geoffrey Gill  
James McBride

Harry Pepe  
Daniel Sauer

The following members of the individual balloting committee voted on this recommended practice. Balloters may have voted for approval, disapproval, or abstention.

Roberto Asano  
Donald Ayers  
Barry Beaster  
Steven Bezner  
Wallace Binder  
Thomas Blackburn  
Jeffrey Britton  
Paul Cardinal  
John Crouse  
Gary Donner  
Jorge Fernandez Daher  
Namal Fernando  
Bruce Forsyth  
Derek Foster  
Michael Franchek  
Fredric Friend  
Carlos Gaytan  
Randall Groves  
Ajit Gwal  
Said Hachichi  
Jeffrey Helzer  
Mohammad Iman  
Richard Jackson  
John Kay  
Gael Kennedy  
Vladimir Khalin  
Yuri Khersonsky

Gary King  
Axel Kraemer  
Jim Kulchisky  
Saumen Kundu  
John Lackey  
Chung-Yiu Lam  
Benjamin Lanz  
William Larzelere  
Aleksandr Levin  
Jinesh Malde  
Richard Marek  
Lee Matthews  
Omar Mazzoni  
William McBride  
Nigel Mcquin  
Joseph Melanson  
Arthur Molden  
Daniel Mulkey  
Gary Murphy  
Eya Musgrove  
Ali Naderian Jahromi  
K. R. M. Nair  
Michael Newman  
Lorraine Padden  
Bansi Patel  
Dhiru Patel

Brian Penny  
Christopher Petrola  
Alvaro Portillo  
Julien Probst  
Johannes Rickmann  
Thomas Rozek  
Daniel Sauer  
Bartien Sayogo  
Nikunj Shah  
Stephen Shull  
Charles Simmons  
Jeremy Smith  
Jerry Smith  
Steve Snyder  
Sanjib Som  
Ronald Stahara  
Wayne Stec  
Susmitha D. Tarlapally  
David Tepen  
Alan Traut  
Roger Verdolin  
John Vergis  
Jane Verner  
Sukhdev Walia  
John Wang  
Alan Wilks  
Jennifer Yu

When the IEEE-SA Standards Board approved this recommended practice on 7 December 2016, it had the following membership:

**Jean-Philippe Faure**, *Chair*  
**Ted Burse**, *Vice Chair*  
**John D. Kulick**, *Past Chair*  
**Konstantinos Karachalios**, *Secretary*

Chuck Adams  
Masayuki Ariyoshi  
Stephen Dukes  
Jianbin Fan  
J. Travis Griffith  
Gary Hoffman

Ronald W. Hotchkiss  
Michael Janezic  
Joseph L. Koepfinger\*  
Hung Ling  
Kevin Lu  
Annette D. Reilly  
Gary Robinson

Mehmet Ulema  
Yingli Wen  
Howard Wolfman  
Don Wright  
Yu Yuan  
Daidi Zhong

\*Member Emeritus

## Introduction

This introduction is not part of IEEE Std C57.138™-2016, IEEE Recommended Practice for Routine Impulse Tests for Distribution Transformers.

The routine impulse test for distribution transformers was proposed and developed by manufacturers of small distribution transformers as a means of including a simplified and reliable impulse test into their routine test procedures.

This recommended practice was first published in 1998 and was the result of almost a decade of working group discussion that progressed through multiple drafts. The intent was to document not just a test procedure but to include a compendium of tutorial information to enable testing engineers and operators to better understand the test procedures necessary to a successful implementation of the routine impulse test.

Included in this document are sections on the design of the impulse test circuit and how it was adapted for use with a wide range of distribution transformers, test circuit connection diagrams for single- and three-phase transformers, recommended fault detection methods, and the use of analog and digital fault detection systems.

Since its first publication there have been only minor changes made to the original, which does indicate the efficacy of this document.

## Contents

1. Overview.....	12
1.1 Scope.....	12
1.2 Purpose.....	12
2. Normative references .....	12
3. Acronyms and abbreviations .....	13
4. General test procedures .....	13
5. Fault detection methods.....	13
6. Circuits for routine impulse testing .....	13
6.1 Impulse wave shape.....	13
6.2 Transformer connections .....	15
6.3 Grounding consideration .....	25
7. Neutral current detection circuit .....	26
7.1 Ground current circuit .....	26
7.2 Neutral-impedance circuit .....	27
7.3 CT circuit.....	27
8. Failure detection method .....	29
8.1 Detection requirements.....	29
8.2 Comparison of wave shapes .....	29
8.3 Automatic failure detection .....	30
8.4 Special considerations .....	42
9. Verification of detector sensitivity.....	43
Annex A (informative) Distribution transformer voltage distribution and impulse fault detection .....	46

## List of Figures

Figure 1—Typical lightning impulse circuit.....	14
Figure 2—Typical transformer connection for routine impulse testing .....	15
Figure 3—Maximum sensitivity connection .....	16
Figure 4—Connection for single HV bushing .....	17
Figure 5—Connection for internally grounded low-voltage winding.....	17
Figure 6—Connections for internally grounded H2 and X2 .....	18
Figure 7—Connections for two low-voltage terminals .....	18
Figure 8—Single HV and single LV bushing connections.....	19
Figure 9—Standard connection for three-phase wye-wye transformer .....	19
Figure 10—Connections for wye-wye transformer with internal HO-XO link .....	20
Figure 11—Connection for wye-wye transformer with internal grounds .....	20
Figure 12—Standard connection for wye-delta transformer .....	21
Figure 13—Connection for wye-delta transformer with internal HO ground.....	21
Figure 14—Delta-delta connections.....	22
Figure 15—Alternate connection for Phase A on delta-delta transformer .....	22
Figure 16—Standard connection for delta-wye transformer .....	23
Figure 17—Alternate connection for Phase A on delta-wye transformer .....	23
Figure 18—Delta-wye connection with internal XO ground.....	24
Figure 19—Connection to limit secondary voltage .....	25
Figure 20—Connection to limit-secondary voltage with internal grounds .....	25
Figure 21—Neutral impedance current detector circuit .....	27
Figure 22—CT type current detector circuit.....	28
Figure 23—Comparison of neutral-impedance curves.....	30
Figure 24—Analog fault detector.....	31
Figure 25—Signal into detector voltage sensor.....	32
Figure 26—Fault detector with immediate comparator.....	32
Figure 27—Current comparison mismatch .....	33
Figure 28—Current curve no fault .....	34
Figure 29—Voltage curve, ground fault .....	35

Figure 30—Current curve, ground fault .....	36
Figure 31—Voltage curve, ground fault .....	37
Figure 32—Current curve, ground fault .....	38
Figure 33—Voltage curves, fault to secondary .....	39
Figure 34—Current curves, fault to secondary .....	39
Figure 35—Neutral impedance curves, comparison of single-turn fault .....	40
Figure 36—Neutral impedance curves, difference of single-turn fault .....	41
Figure 37—Neutral impedance curves, accumulated difference .....	42
Figure 38—Comparison, actual one-turn fault .....	43
Figure 39—Comparison, staged one-turn fault .....	44
Figure A.1—Equivalent capacitance network for single-section layer winding .....	48
Figure A.2—Current flow due to impulse voltage .....	48
Figure A.3—Impulse voltage distribution of a single-section layer-wound coil .....	49
Figure A.4—Equivalent capacitance network for a two-section layer winding .....	50
Figure A.5—Impulse current flow for a two-section layer winding .....	51
Figure A.6—R-C neutral current detector output for a two-section winding .....	52
Figure A.7—Voltage distribution within a two-section winding .....	52
Figure A.8—Three-section layer winding with equivalent capacitances shown .....	55
Figure A.9—Equivalent capacitance network for a three-section layer winding .....	56
Figure A.10—Impulse current wave for a three-section layer winding .....	57
Figure A.11—Impulse voltage distribution within a three-section layer winding .....	58
Figure A.12—Layer-wound coil with a fault within the winding .....	60
Figure A.13—R-C neutral detector output with and without a winding fault .....	60
Figure A.14—Fault from bushing to ground .....	61
Figure A.15—R-C neutral detector output with a fault from bushing to ground .....	62
Figure A.16—Layer-wound coil with a fault from winding to ground .....	63
Figure A.17—R-C neutral shunt detector output with a fault to ground within the winding .....	63
Figure A.18—Effects of core saturation due to application of multiple impulse voltage tests .....	64
Figure A.19—R-C neutral shunt detector with and without core saturation .....	65
Figure A.20—R-C neutral-current detector output with core saturation and with the impulse voltage polarity reversed .....	66

# IEEE Recommended Practice for Routine Impulse Tests for Distribution Transformers

## 1. Overview

### 1.1 Scope

This recommended practice covers routine impulse tests performed on distribution transformers, as required in IEEE Std C57.12.00™, and described in 10.4 of IEEE Std C57.12.90™-2015<sup>1</sup>. Distribution transformers covered by this recommended practice are liquid-immersed, single- and three-phase overhead-type up to 500 kVA; single-phase pad-mounted compartmental-type and underground-type up to 167 kVA; three-phase pad-mounted compartmental-type; and underground-type up to 2500 kVA.

This recommended practice covers only those aspects of impulse testing that are specific to routine testing of distribution transformers. For more thorough coverage of impulse testing of transformers in general, IEEE Std C57.98™ should be consulted.

### 1.2 Purpose

This recommended practice assists manufacturers of distribution transformers in the setup and operation of a routine impulse test, and assists distribution transformer users and purchasers in understanding the routine impulse test and how it differs from design tests.

## 2. Normative references

The following referenced documents are indispensable for the application of this document (i.e., they must be understood and used, so each referenced document is cited in text and its relationship to this document is explained). For dated references, only the edition cited applies. For undated references, the latest edition of the referenced document (including any amendments or corrigenda) applies.

IEEE Std 4™, IEEE Standard Techniques for High-Voltage Testing.<sup>2,3</sup>

IEEE Std 1122™, IEEE Standard for Digital Recorders for Measurements in High-Voltage Impulse Tests.

---

<sup>1</sup>Information on references can be found in [Clause 2](#).

<sup>2</sup>The IEEE standards or products referred to in this clause are trademarks of The Institute of Electrical and Electronics Engineers, Inc.

<sup>3</sup>These publications are available from The Institute of Electrical and Electronics Engineers.